

# 30V, $6m\Omega$ , 30A, Single N-Channel

## 1.Features

- ♦ 30V MOSFET technology
- Low on-state resistance
- Fast switching
- Vgs±20V

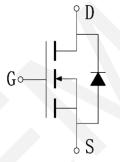
## 2.Applications

- Power Switching Application
- Load Switching





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Schematic Diagram

3.Absolute Max Ratings at Ta=25°C (Note1)					
Parameter	Symbol	Maximum	Units		
Drain to Source Voltage	V <sub>DSS</sub>	30	V		
Gate to Source Voltage	V <sub>GSS</sub>	±20	V		
Drain Current (DC)	Ι <sub>D</sub>	30	А		
Drain Current (Pulse), PW≤300µs	I <sub>DP</sub>	120	А		
Total Dissipation	P <sub>D</sub>	22	W		
Avalanche Energy, Single Pulsed	E <sub>AS</sub>	25	mJ		
Junction Temperature	Tj	150	°C		
Storage Temperature	T <sub>stg</sub>	-55 to +150	°C		

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

## 4.Thermal Resistance Ratings (Note 2)

Parameter	Symbol	Value	Unit
Junction to case	R <sub>θJC</sub>	5.7	°C/W

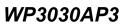
Note 2: When mounted on 1 inch square copper board  $t \le 10$  sec The value in any given application depends on the user's specific board design.



5.Electrical Characteristics at Ta=25°C (Note 3)							
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units	
Drain to Source Breakdown Voltage	V <sub>(BR)DSS</sub>	I <sub>D</sub> = 250μA, V <sub>GS</sub> = 0V	30			V	
Zero-Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS}$ = 30V, $V_{GS}$ = 0V			1	μA	
Gate to Source Leakage Current	I <sub>GSS</sub>	$V_{GS} = \pm 20 V, V_{DS} = 0 V$			±100	nA	
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>DS</sub> =250µA	1.0		2.5	V	
Static Drain to Source On-State Resistance		I <sub>D</sub> = 25A, V <sub>GS</sub> = 10V		6	7.2	mΩ	
	R <sub>DS(on)</sub>	I <sub>D</sub> = 15A, V <sub>GS</sub> = 4.5V		10	12	mΩ	
Input Capacitance	Ciss	V <sub>GS</sub> =0V,		1120		pF	
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> =15V,		190		рF	
Reverse Transfer Capacitance	Crss	Frequency=1.0MHz		150		pF	
Turn-ON Delay Time	t <sub>d(on)</sub>			8		ns	
Rise Time	tr	V <sub>DD</sub> = 15V, I <sub>DS</sub> = 30A,		100		ns	
Turn-OFF Delay Time	t <sub>d(off)</sub>	$V_{GS}$ = 10V, $R_G$ = 3 $\Omega$		23		ns	
Fall Time	t <sub>f</sub>			108		ns	
Total Gate Charge	Qg	V <sub>DS</sub> = 15V,		24		nC	
	Q <sub>gs</sub>	V <sub>GS</sub> = 10V,		4		nC	
	Q <sub>gd</sub>	I <sub>DS</sub> = 15A		6		nC	
Diode Forward Voltage	V <sub>FSD</sub>	$I_{\rm S}$ = 30A, $V_{\rm GS}$ = 0			1.2	V	

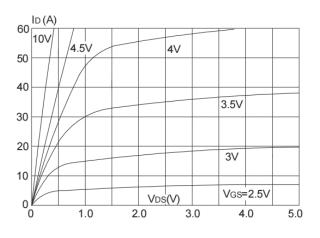
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Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

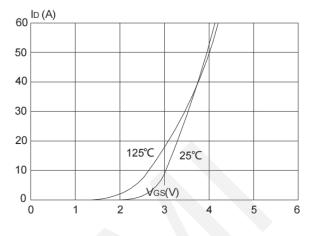


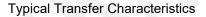


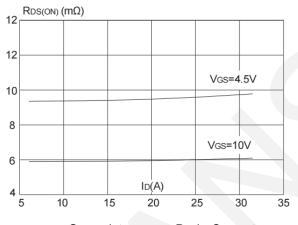
## 6.Typical electrical and thermal characteristics

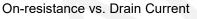


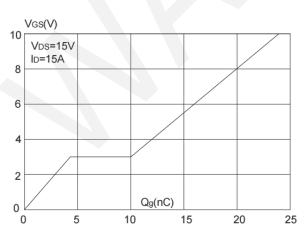
## **Output Characteristics**



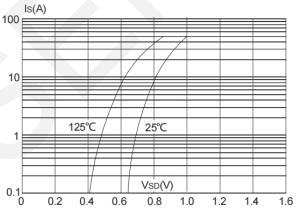




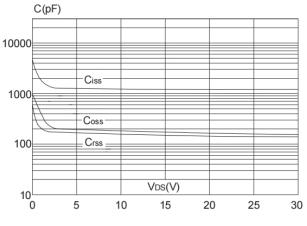




Gate Charge Characteristics

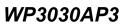


**Body Diode Characteristics** 

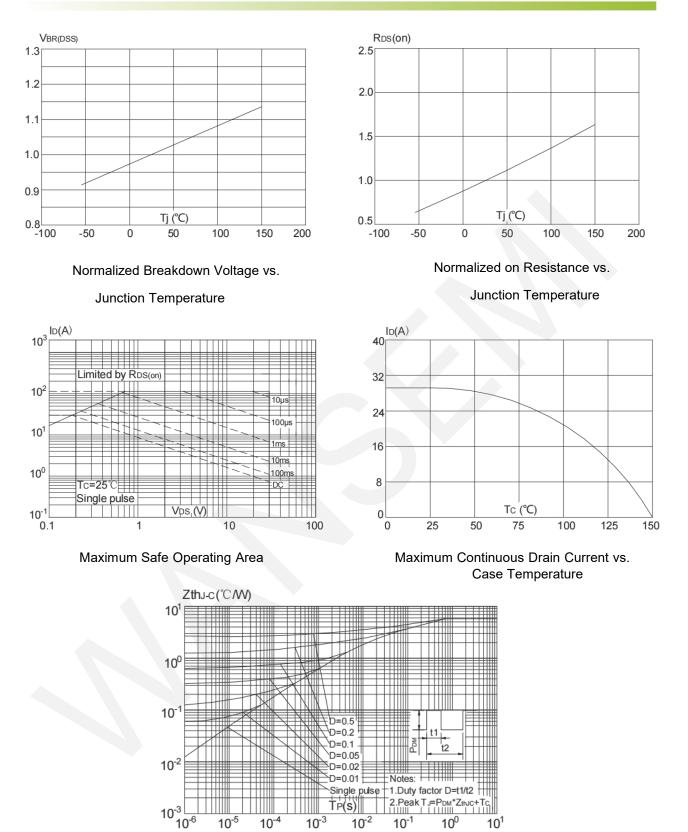


**Capacitance Characteristics** 

Rev.0.1



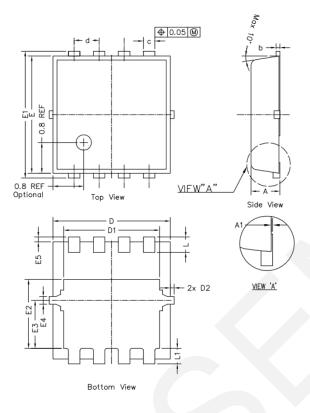




Maximum Effective Transient Thermal Impedance, Junction-to-Case



## 7.Package Dimensions



SAMBOLS	DIMENSION IN MM			DIMENSION IN INCHES		
SYMBOLS	MIN	NOM	MAX	MIN	NOM	MAX
А	0.700	0.750	0.800	0.028	0.030	0.031
A1			0.050			0.002
b	0.144	0.152	0.202	0.006	0.006	0.008
с	0.250	0.300	0.350	0.010	0.012	0.014
d	0.65 BSC		0.026 BSC			
D	2.950	3.050	3.150	0.116	0.120	0.124
D1	2.390	2.490	2.590	0.094	0.098	0.102
D2			0.125			0.005
E	2.950	3.050	3.150	0.116	0.120	0.124
E1	3.200	3.300	3.400	0.126	0.130	0.134
E2	1.700	1.800	1.900	0.067	0.071	0.075
E3	1.150	1.250	1.350	0.045	0.049	0.053
E4	0.150	0.200	0.250	0.006	0.008	0.010
E5	0.075	0.125	0.175	0.003	0.005	0.007
Ĺ	0.300	0.400	0.500	0.01	0.02	0.02
L1	0.300	0.400	0.500	0.01	0.02	0.02



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